

William Paul

List of Publications by Year in descending order

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Version: 2024-02-01

20
papers

1,336
citations

567281

15
h-index

794594

19
g-index

20
all docs

20
docs citations

20
times ranked

1485
citing authors

#	ARTICLE	IF	CITATIONS
1	Reading and writing single-atom magnets. <i>Nature</i> , 2017, 543, 226-228.	27.8	319
2	Electron paramagnetic resonance of individual atoms on a surface. <i>Science</i> , 2015, 350, 417-420.	12.6	280
3	Coherent spin manipulation of individual atoms on a surface. <i>Science</i> , 2019, 366, 509-512.	12.6	109
4	Control of the millisecond spin lifetime of an electrically probed atom. <i>Nature Physics</i> , 2017, 13, 403-407.	16.7	97
5	Atomic-scale sensing of the magnetic dipolar field from single atoms. <i>Nature Nanotechnology</i> , 2017, 12, 420-424.	31.5	96
6	Engineering the Eigenstates of Coupled Spin- $\frac{1}{2}$ Atoms on a Surface. <i>Physical Review Letters</i> , 2017, 119, 227206.	7.8	78
7	Probing quantum coherence in single-atom electron spin resonance. <i>Science Advances</i> , 2018, 4, eaag1543.	10.3	78
8	Tuning the Exchange Bias on a Single Atom from 1 mT to 10 mT. <i>Physical Review Letters</i> , 2019, 122, 227203.	7.8	54
9	Minimum Threshold for Incipient Plasticity in the Atomic-Scale Nanoindentation of Au(111). <i>Physical Review Letters</i> , 2013, 110, 135506.	7.8	42
10	Generation of constant-amplitude radio-frequency sweeps at a tunnel junction for spin resonance STM. <i>Review of Scientific Instruments</i> , 2016, 87, 074703.	1.3	40
11	High-resolution friction force microscopy under electrochemical control. <i>Review of Scientific Instruments</i> , 2010, 81, 083701.	1.3	36
12	Conductivity of an atomically defined metallic interface. <i>Proceedings of the National Academy of Sciences of the United States of America</i> , 2012, 109, 19097-19102.	7.1	25
13	Refined tip preparation by electrochemical etching and ultrahigh vacuum treatment to obtain atomically sharp tips for scanning tunneling microscope and atomic force microscope. <i>Review of Scientific Instruments</i> , 2011, 82, 113903.	1.3	24
14	Implementation of atomically defined field ion microscopy tips in scanning probe microscopy. <i>Nanotechnology</i> , 2012, 23, 335702.	2.6	16
15	Indentation-formed nanocontacts: an atomic-scale perspective. <i>Physical Chemistry Chemical Physics</i> , 2014, 16, 8201-8222.	2.8	15
16	FIM tips in SPM: Apex orientation and temperature considerations on atom transfer and diffusion. <i>Applied Surface Science</i> , 2014, 305, 124-132.	6.1	9
17	Note: Electrochemical etching of sharp iridium tips. <i>Review of Scientific Instruments</i> , 2011, 82, 116105.	1.3	7
18	Transient adhesion and conductance phenomena in initial nanoscale mechanical contacts between dissimilar metals. <i>Nanotechnology</i> , 2013, 24, 475704.	2.6	6

#	ARTICLE	IF	CITATIONS
19	Simple Si(111) surface preparation by thin wafer cleavage. Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films, 2013, 31, .	2.1	3
20	Field Ion Microscopy for the Characterization of Scanning Probes. , 2015, , 159-198.		2